

Test Report

No. :KA/2007/81879 Date: 2007/09/07 Page: 1 of 3


RALEC ELECTRONIC CORPORATION
 NO.1, CENTRAL 2nd STREET, NANTZE EXPORT PROCESSING ZONE, KAOHSIUNG
 ,TAIWAN.



The following sample(s) was/were submitted and identified by/on behalf of the client as :

Sample Description : LEAD FREE CHIP RESISTOR PRODUCT
 Style/Item No. : RTT20(2010T)RTT20J101
 Color : SILVER/BLACK
 Sample Receiving Date : 2007/08/31
 Testing Period : 2007/08/31 TO 2007/9/7

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Test Requested : In accordance with the RoHS Directive 2002/95/EC, and its amendment directives.
Test Method : (1) With reference to US EPA Method 3050B for Lead Content. Analysis was performed by ICP-AES.
Test Result(s) : Please refer to next page(s).


Katherine Ho / Supervisor
 Signed for and on behalf of
 SGS Taiwan Limited

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